

Real-Time Determination of Compositional Profiles in Structured Materials Using Laser Ablation and LA-ICPMS

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Laser ablation in applications

- Micro machining
- 3D texturing and sintering
- Chemical analysis

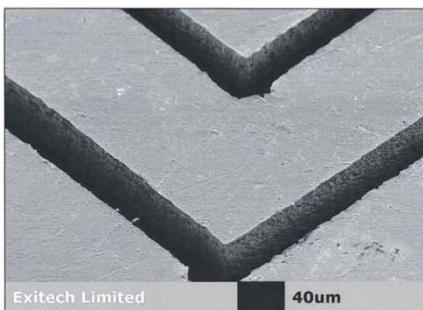
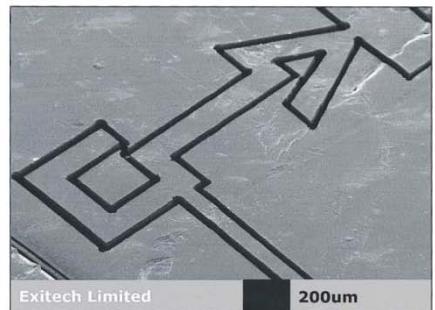


Fig. 5. Samples of FEP micromachined using a femtosecond laser.



Glass samples micromachined using a femtosecond laser.

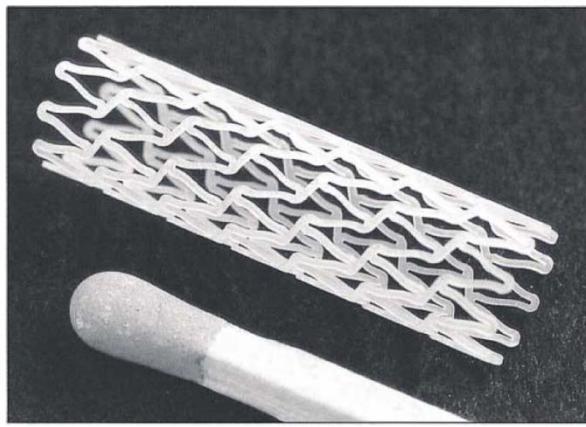
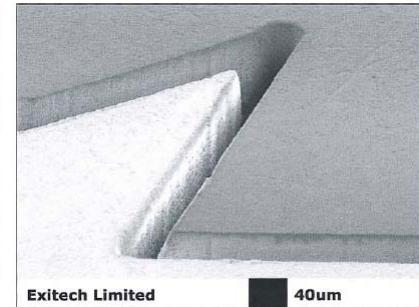
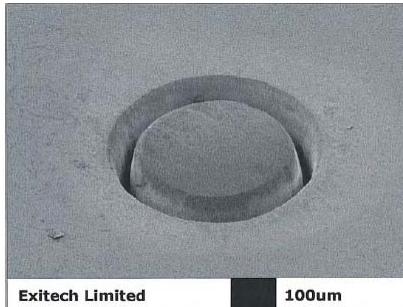
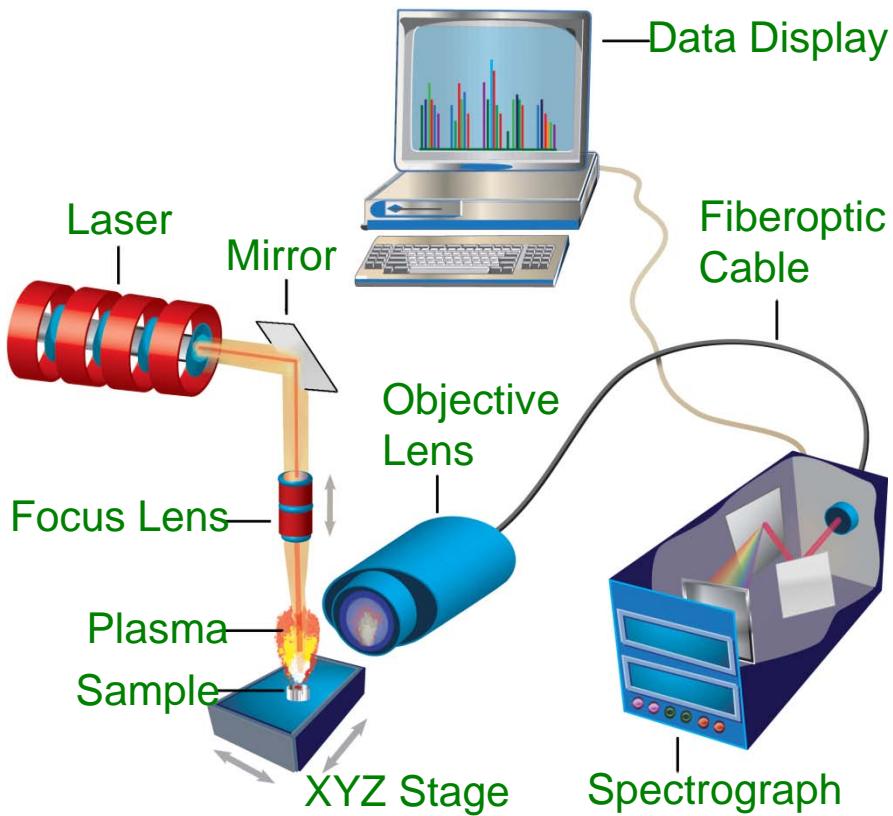


Fig. 12. A medical stent micromachined from a biodegradable polymer using a femtosecond laser (Courtesy of LZH/Cortronik).

RIKEN Review No. 50 (January, 2003): Focused on Laser Precision Microfabrication (LPM 2002)

Laser ablation chemical analysis

LIBS principle of operation:



Laser-induced breakdown spectroscopy (LIBS)

- Simple, rapid, real-time
- Any kind of sample
- No sample preparation
- High spatial resolution $\sim 10 \mu\text{m}$
- Mapping, depth-profiling

Commercial LIBS and LA-ICPMS



RT100



ns-LIBS, 20 Hz

J100-UV



femto-LA-ICPMS, 100 kHz

- Isotopic & elemental analysis
- Simple, rapid, real-time
- Any kind of sample
- No sample preparation
- High spatial resolution
- Minimum fractionation
- Mapping, depth-profiling

λ, nm λ, nm
266 343
532 1030
1064

(150 μJ)

Patented

www.appliedspectra.com

Tandem LA-LIBS: OES & ICPMS



LA-LIBS, Nd:YAG, 5 ns, 20 Hz

www.appliedspectra.com

λ , nm	
213	4.5 mJ
266	25 mJ
532	55 mJ
1064	100 mJ



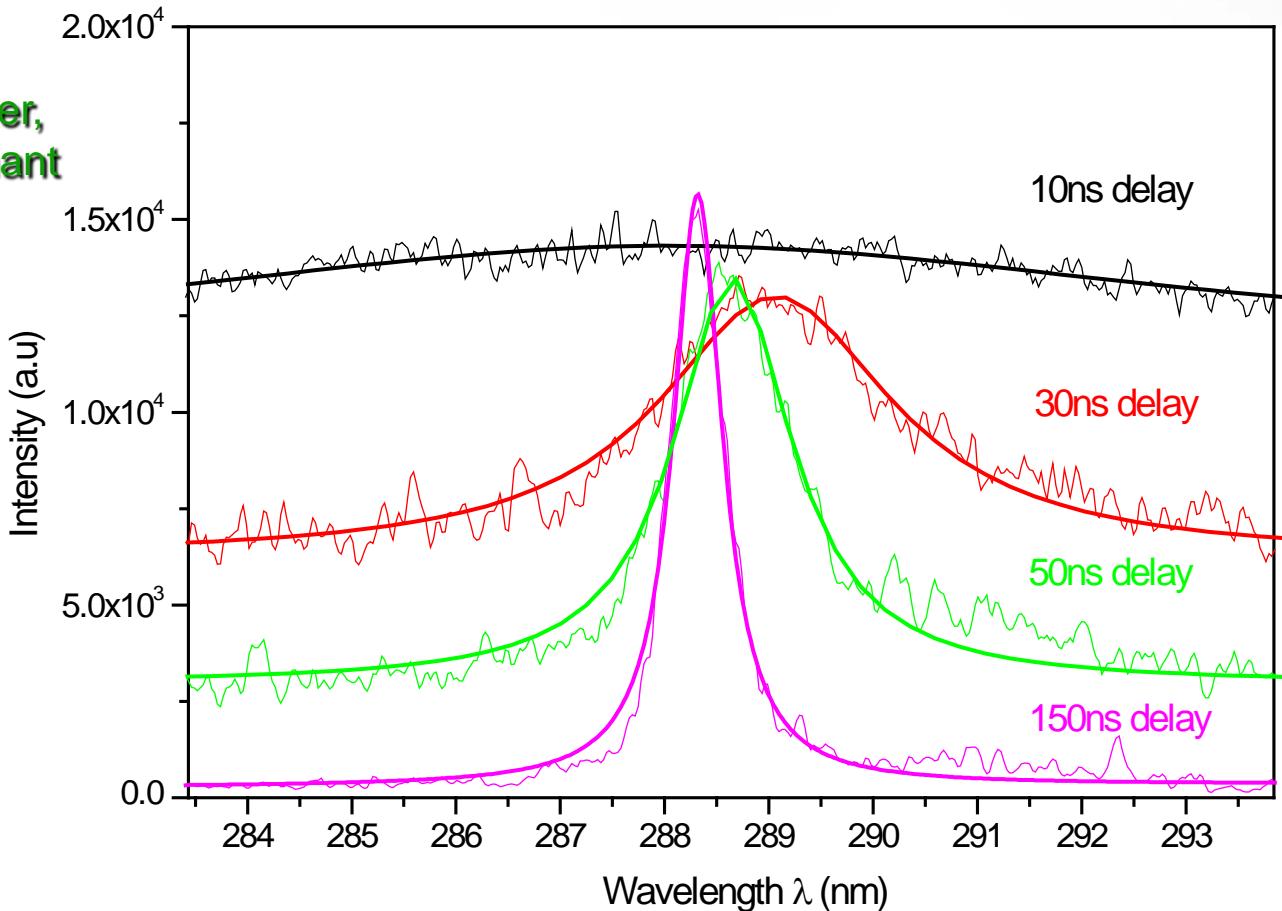
Patent Pending

- Emission and MS simultaneously
- Normalization of isotopic ICPMS
- All elements including H, C, N, O
- Modular, easily upgradable
- Up to Two LIBS spectrographs
- Easy upgrade to fs-LA-ICPMS
- Isotopic & elemental analysis
- Simple, rapid, real-time
- Any kind of sample
- No sample preparation
- High spatial resolution
- Rapid mapping, depth-profiling

Line broadening and shift

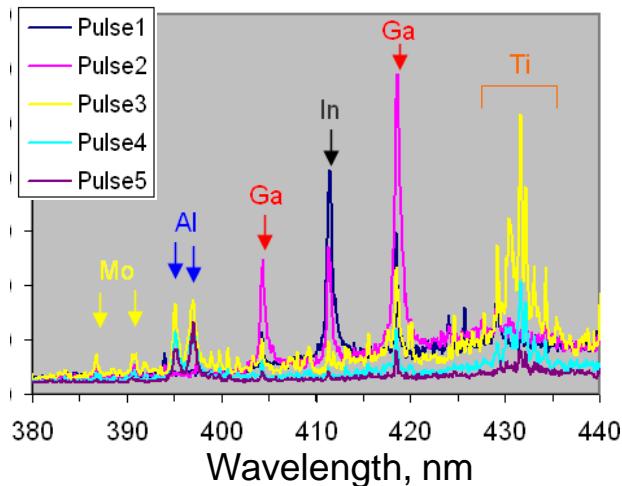
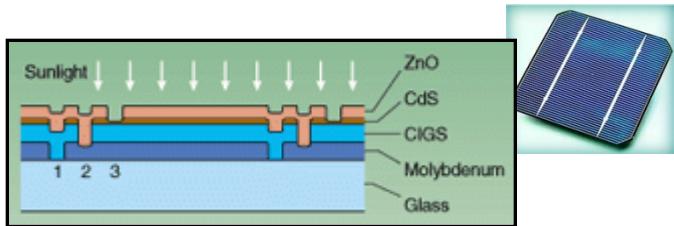


- Broadening: Stark, Doppler, collisional, resonant
- Continuum radiation:
- Free electron-ion recombination
- Bremsstrahlung



Depth profiling analysis

Solar cell structure



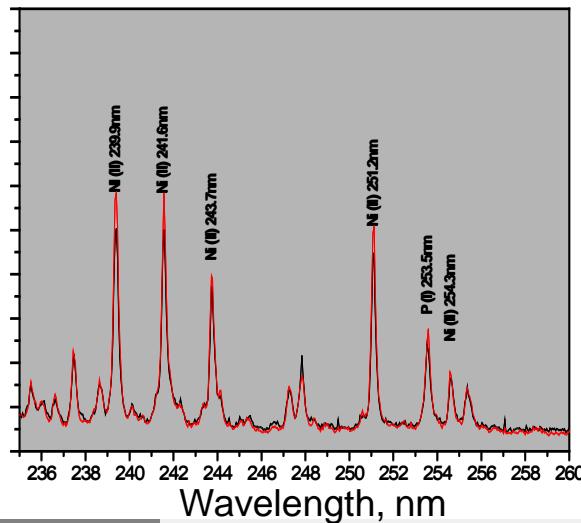
- Depth resolution ~20 nm

e-Storage substrate

Lubricant, ~1 nm
Carbon overcoat, <15 nm
Magnetic layer, ~30 nm
Cr underlayer, ~50 nm
NiP Ni-P sublayer, ~10,000 nm
Aluminum Metal substrate

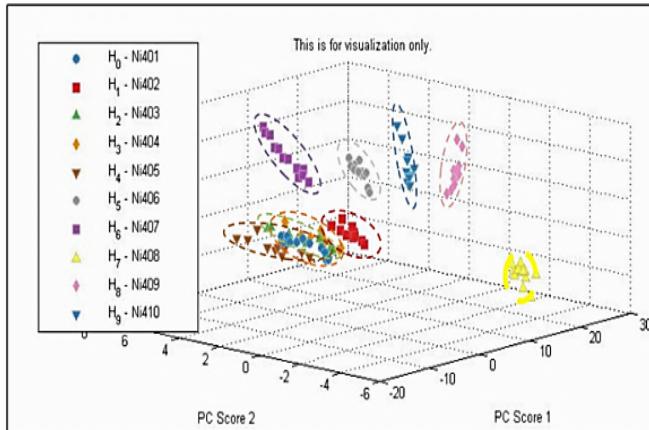
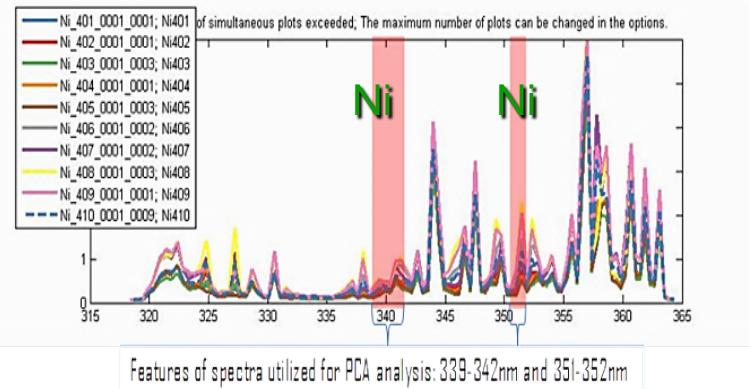


Uniformity of 150 nm NiP layer

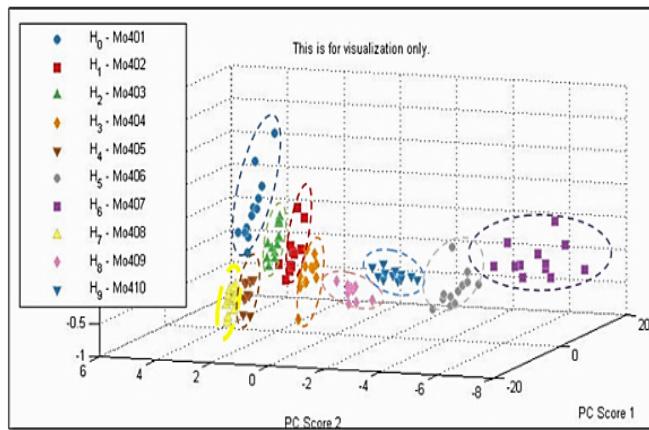
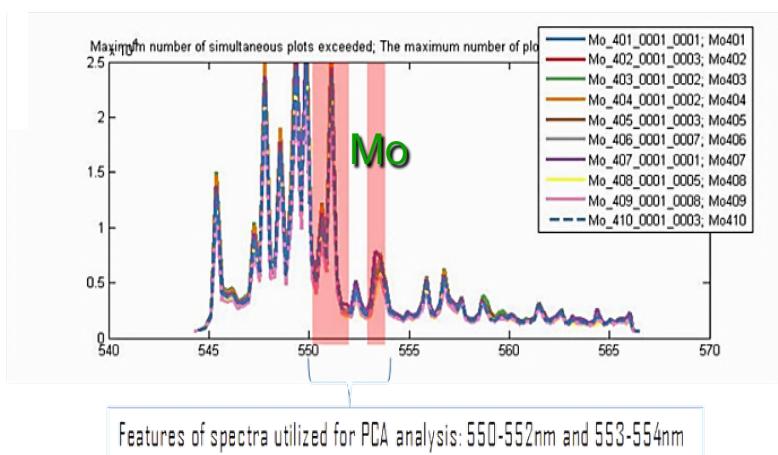


Discrimination of materials

Raw materials: 10 steel samples classified using PCA and PLS-DA

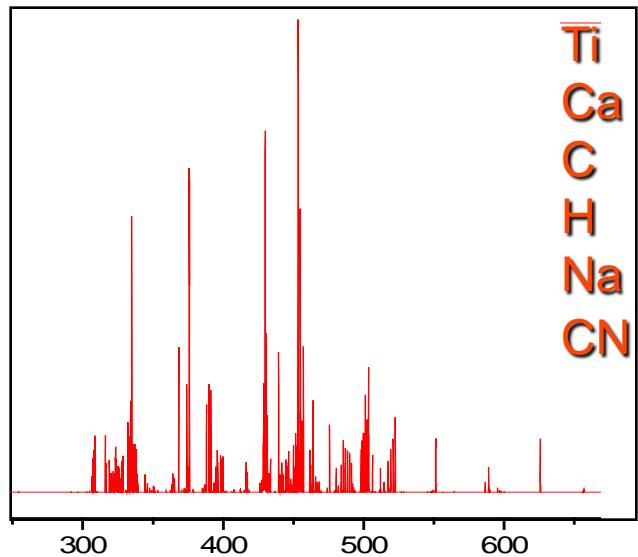


- $\lambda = 1064 \text{ nm}$
- ppm sensitivity
- fast discrimination

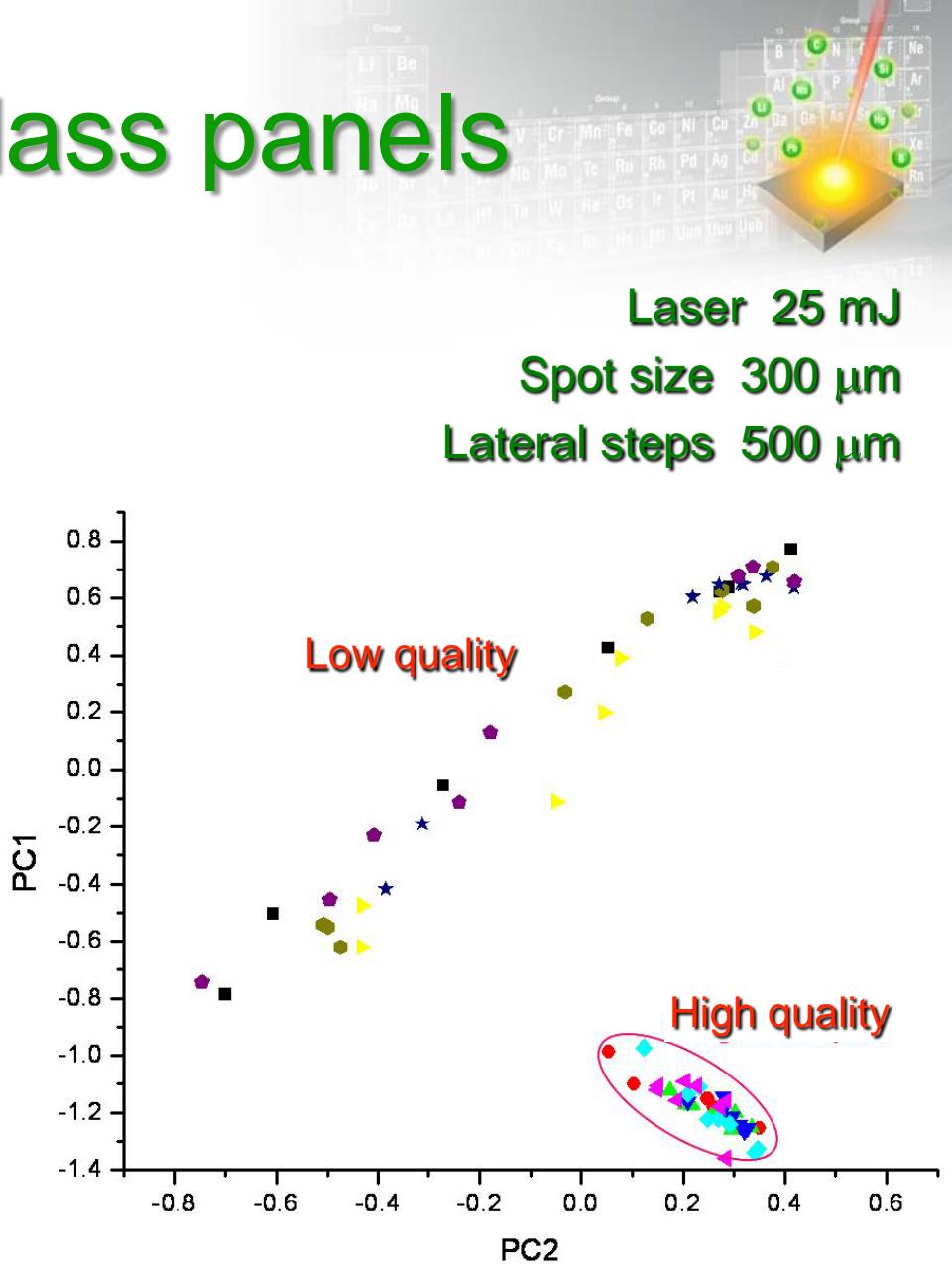


- Not possible by XRF
- Too slow by ICP

Quality of fiberglass panels

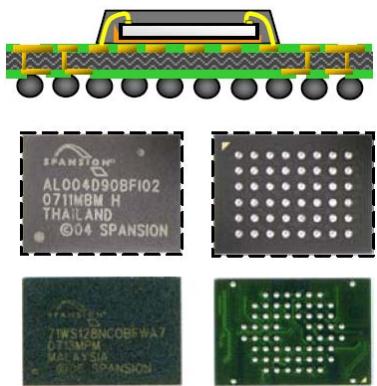


- PCA discrimination of high vs low quality of fiberglass coatings
- High-quality samples consistently demonstrate similar spectra



Discrimination of solders

High-lead vs. low-lead

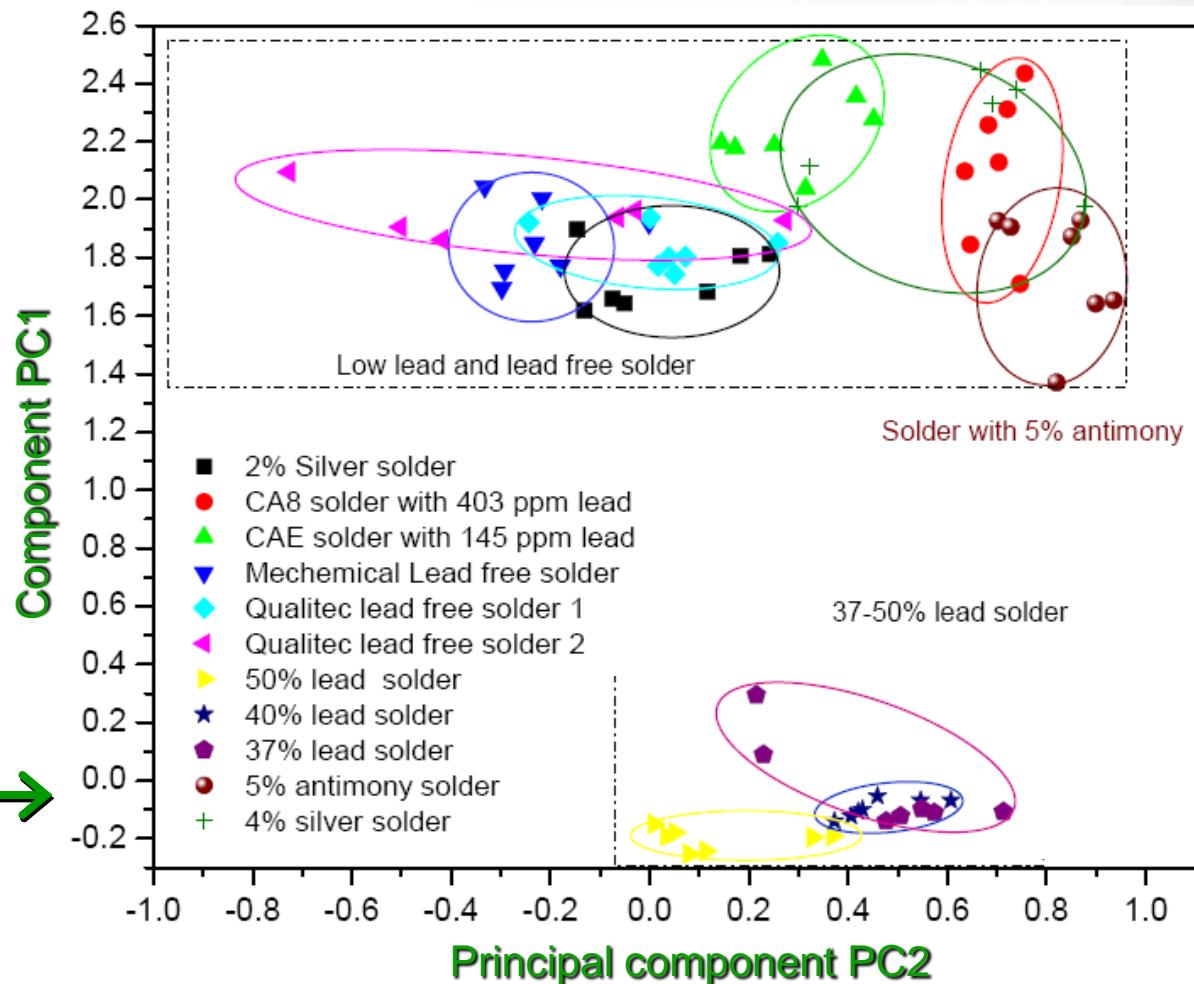


Thin plated solder leads
and solder balls in chips

12 different solders tested

(RoHS limit <0.1% Pb)

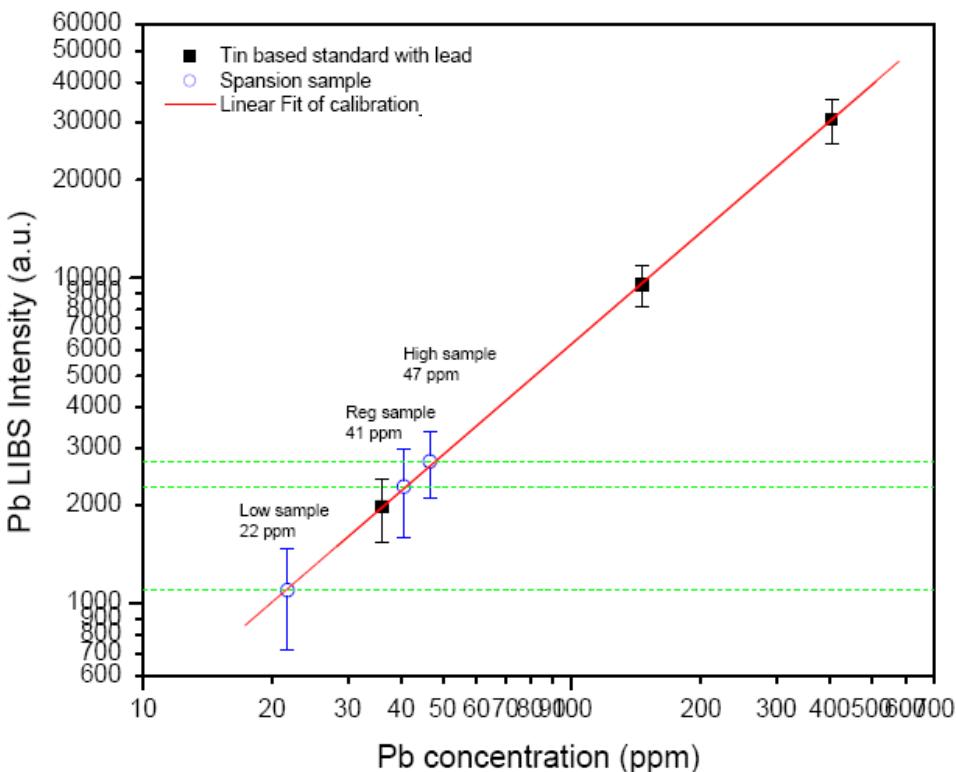
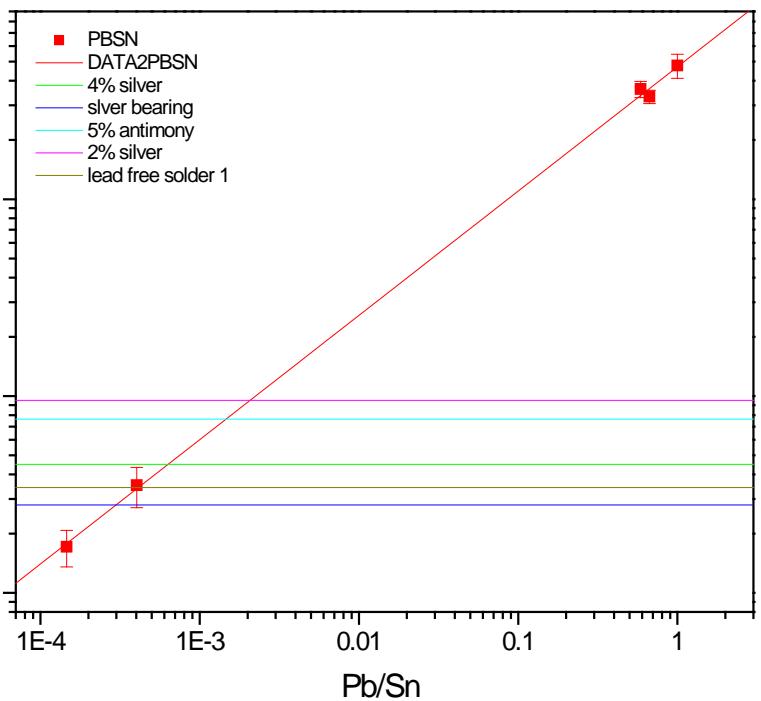
- Library spectra stored



LIBS calibration for Pb



Pb/Sn LIBS Intensity (a.u.)

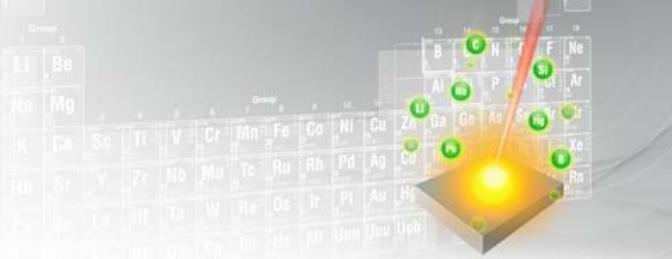


Quantitative analysis of electrical solders and solder platings

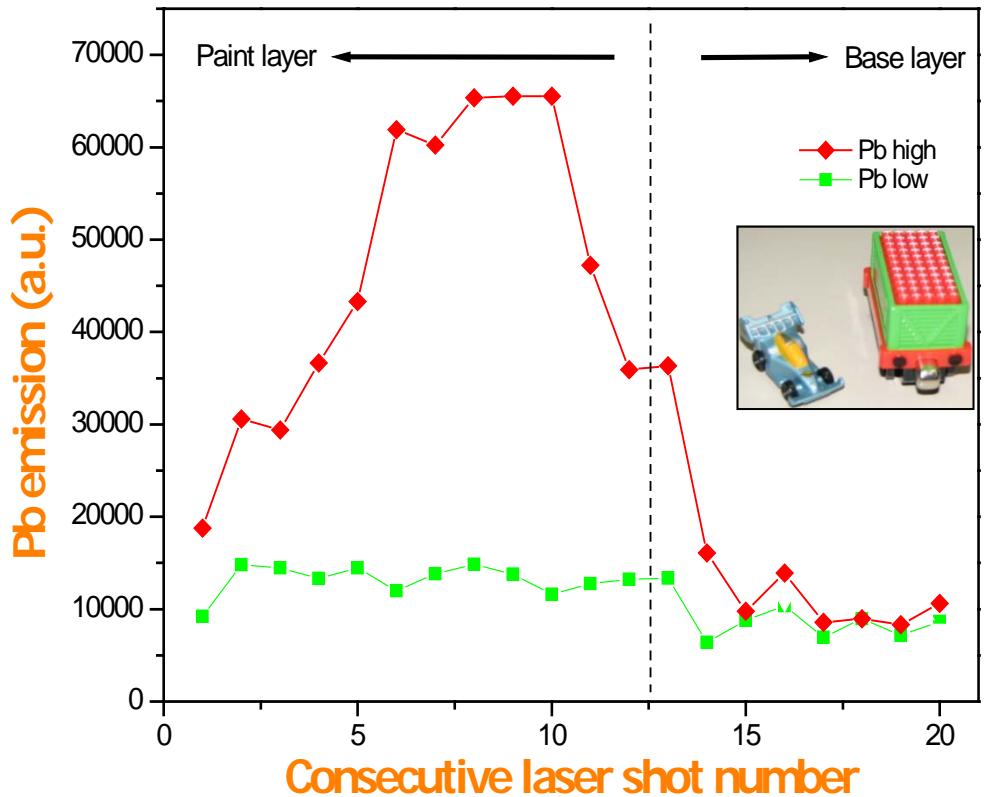
<10 sec per sample

Pb detection limit <10ppm

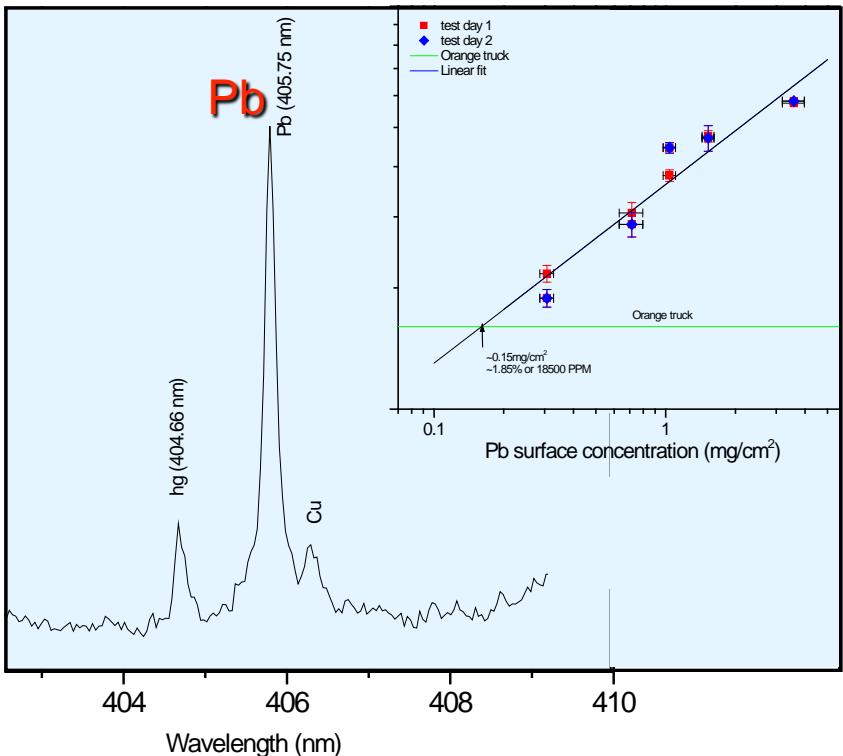
Lead in paint and toys



Depth resolution ~0.5 μm



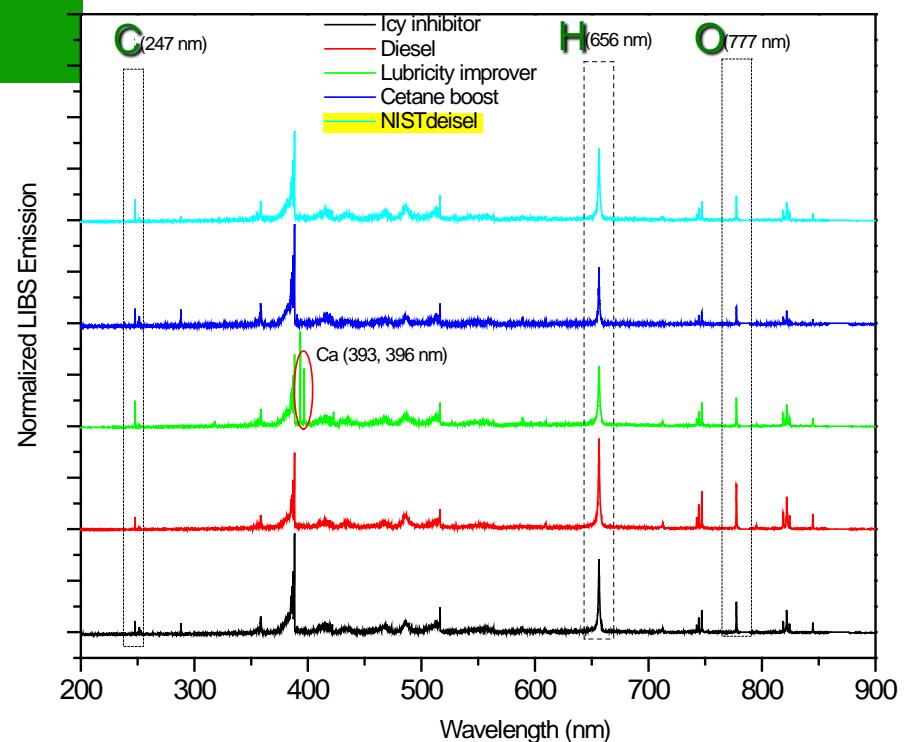
Standard sample/calibration for Pb



Detection limits: 15 ppm Pb (0.1 $\mu\text{g}/\text{cm}^2$)

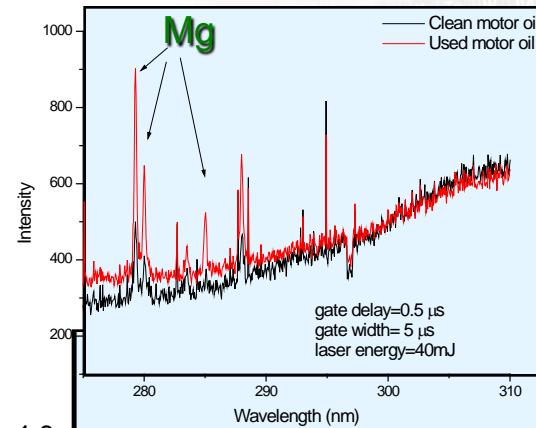
CPSC rule: 300 ppm
90 ppm in paint

Motor oil, diesel and additives

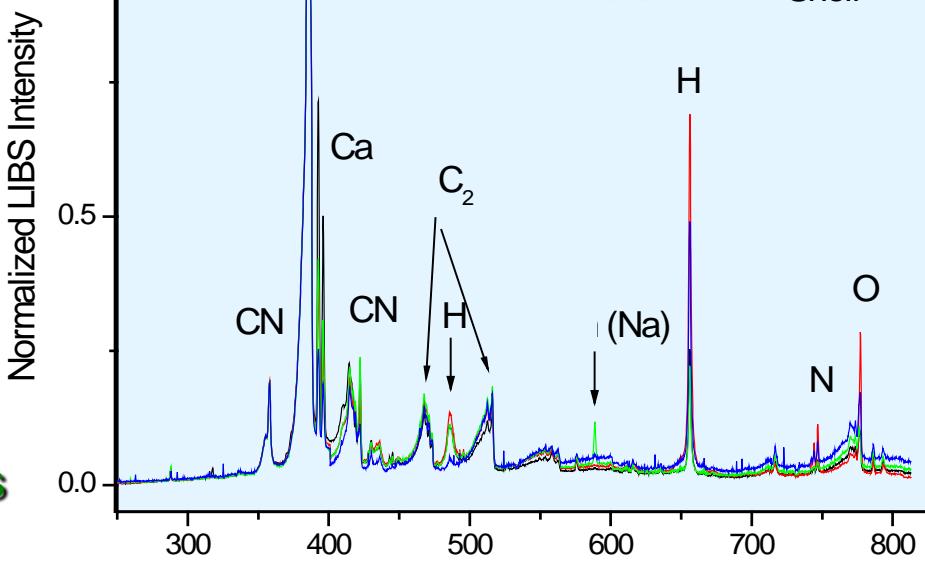


Contaminant detection level: ~40 ppm
(may include particulates)

PLS analysis discriminates fuels and oils

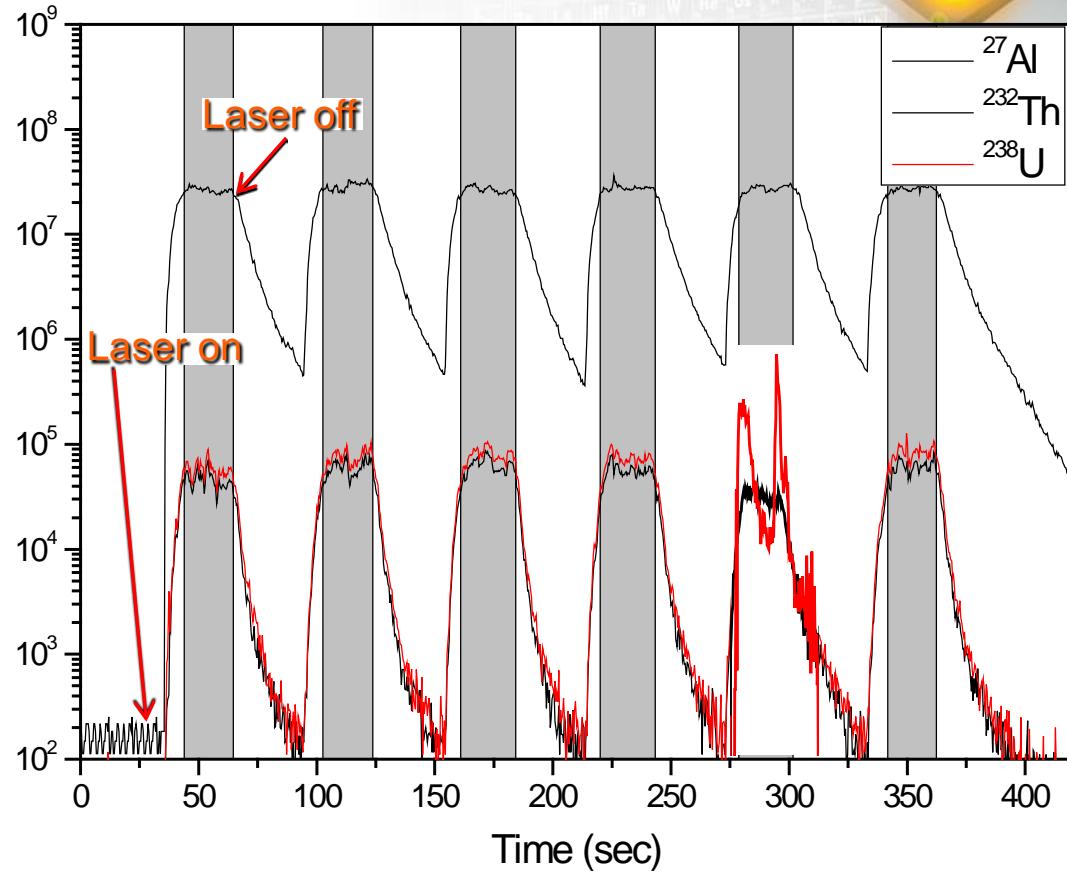
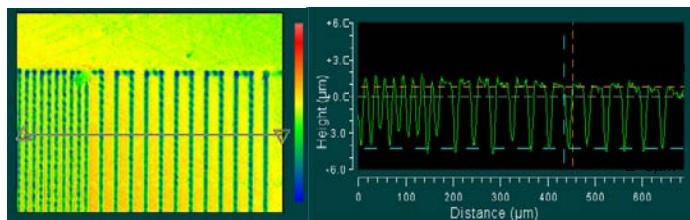


10W-30



High repetition LA-ICPMS

Glass samples

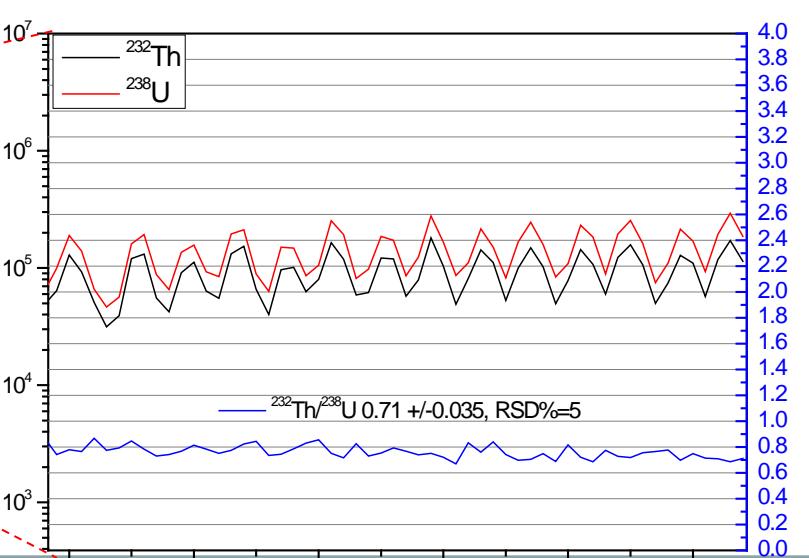
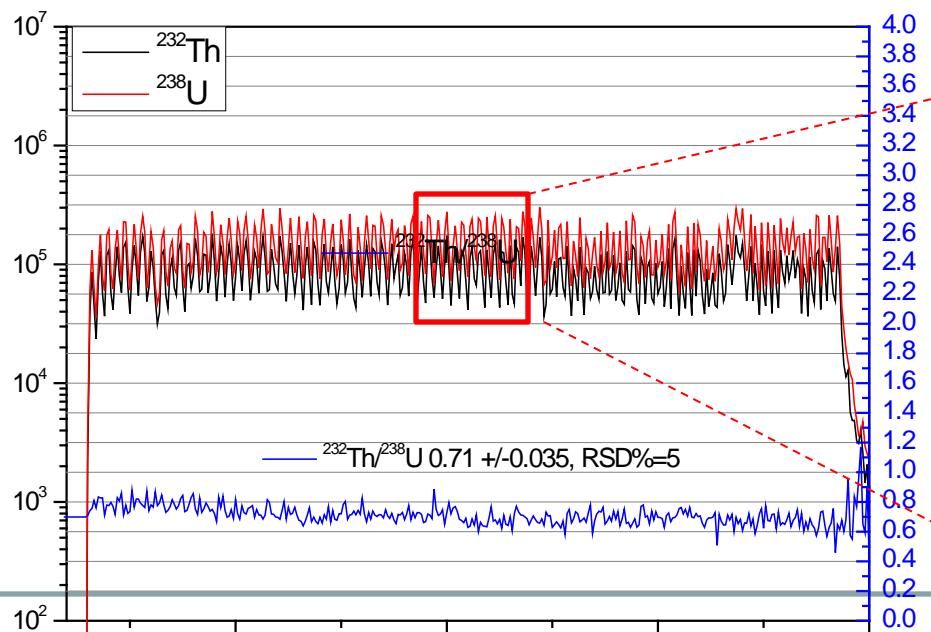


Concentration of ^{232}Th , ^{238}U – 37 $\mu\text{g/g}$

Laser repetition rate – 20 kHz ($\lambda=343\text{ nm}$)

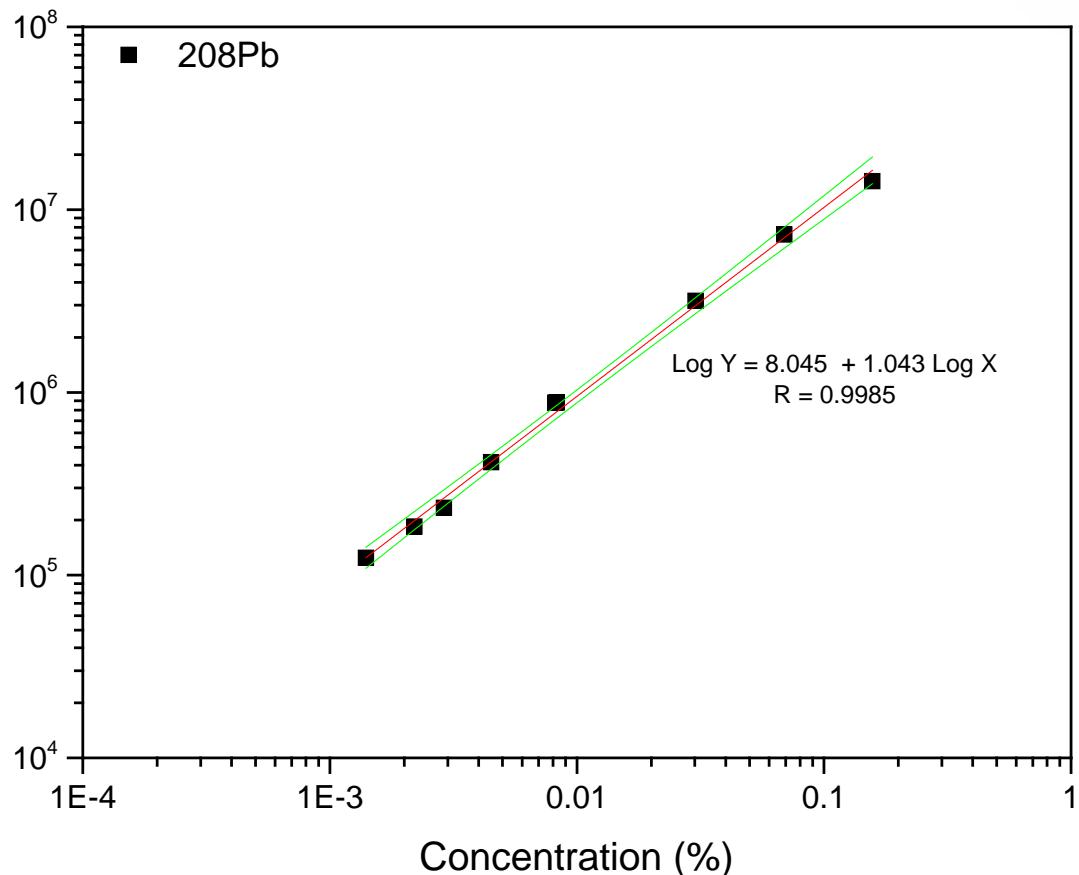
Stage moving speed – 20 mm/s

Quasi-continuous LA scanning



^{232}Th , ^{238}U intensities and their ratio at repetition rate of 20kHz

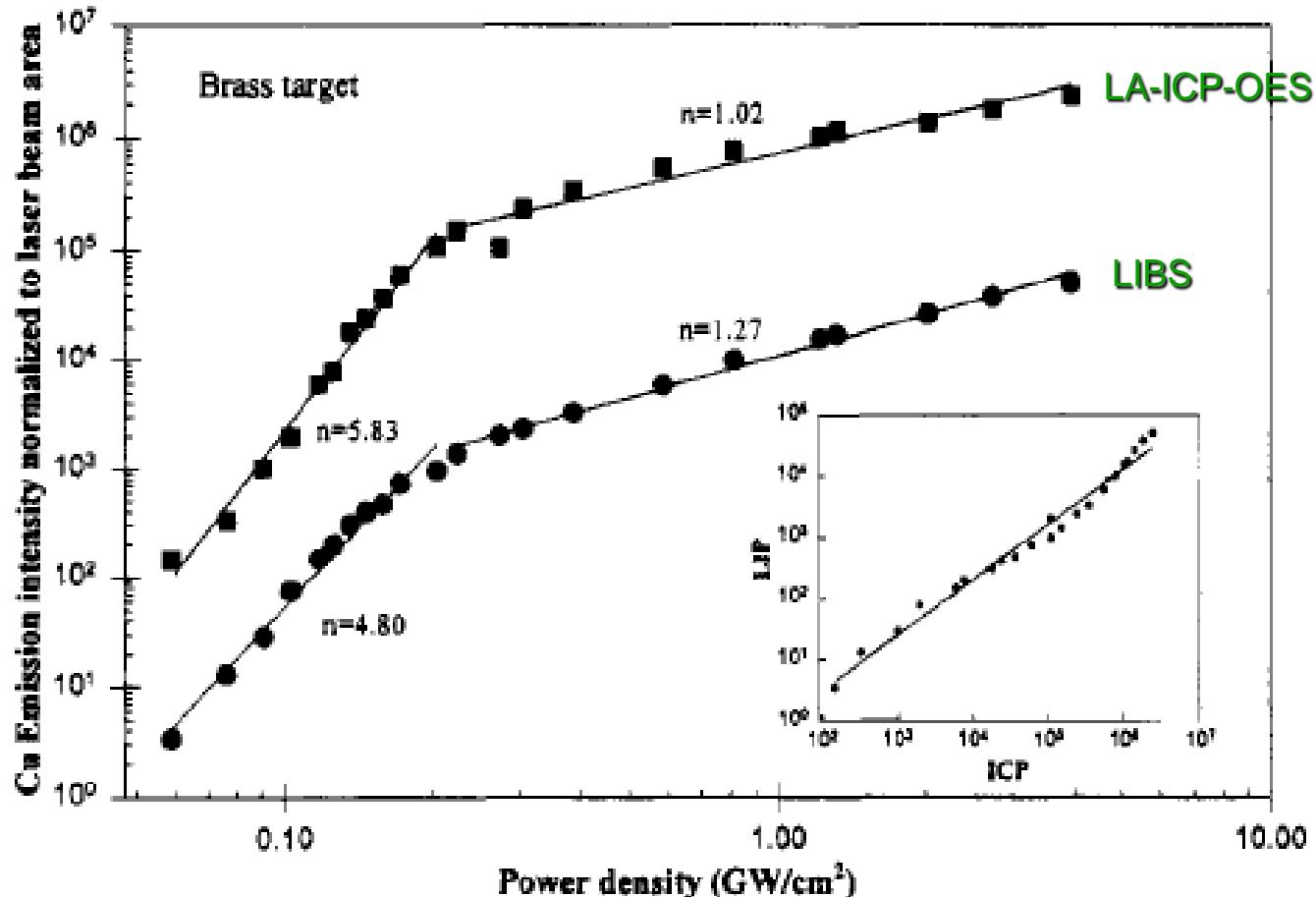
Quantitative LA-ICPMS results



- Lead in zinc alloys
- Linear calibration

$\lambda = 343\text{nm}$
Laser energy ~0.1 mJ
Fluence ~20 J/cm²
Spot size ~ 25 μm
Repetition rate 0.1 kHz
Scan speed – 0.1 mm/s

Correlation of LIBS and LA-ICP

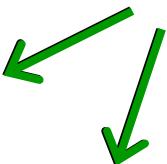


A. Fernandez, X.L Mao, W.T. Chan, M.A. Shannon, R.E. Russo, "Correlation of spectral emission intensity in the inductively coupled plasma and laser-induced plasma during laser ablation of solid samples" – 1995

Conclusion

- Fast (seconds)
- Sensitive (ppm, ppb)
- No sample prep
- Elemental, isotopic
- Organic and inorganic
- Universal for any sample
- Lateral and depth profiling →
- Commercially available models

**LIBS, LA-ICP-MS
in tandem**



→
~3 µm; ~10 nm
electronics
optical devices
protective coatings
pharmaceutical coatings
micro-mechanical, MEMS
new modified materials

Thank you



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